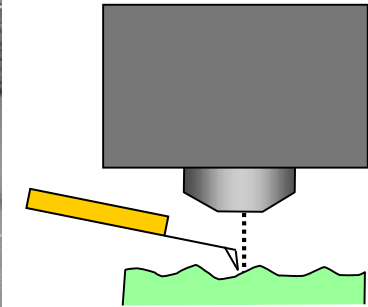
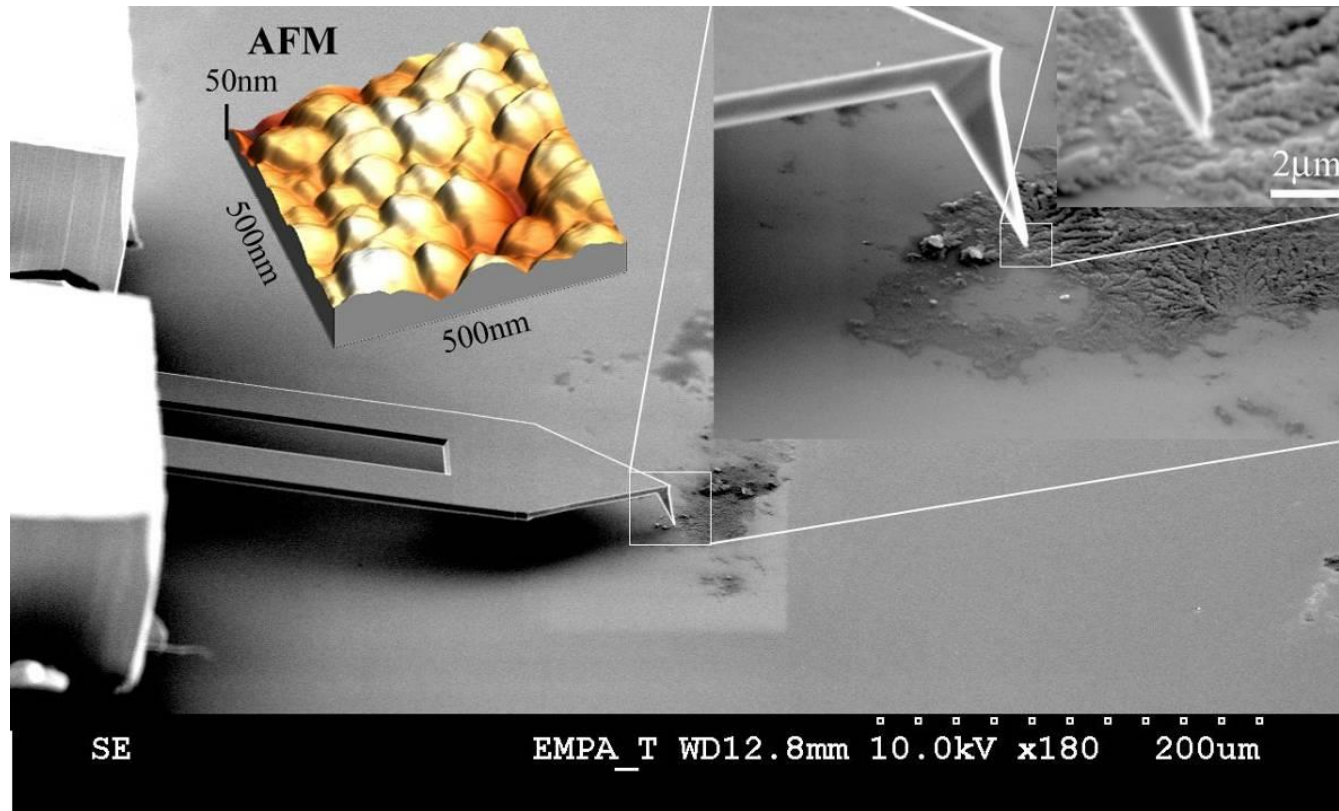




## Use in SEM

- Use of Akiyama-Probe in SEM (scanning electron microscope) is feasible in practice. However, NANOSENSORS does not guarantee a correct operation of Akiyama-Probe in such environment. Please use the probe at your own responsibility.



EMPA (Switzerland), Dr. Vinzenz Friedli, "Focused electron- and ion-beam induced processes : in situ monitoring, analysis and modeling," dissertation EPFL, no 4036 (2008).

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